

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10595157	TAKENAKA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	John L Goff	1791

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
156	307.1,307.7	7/31/08	JLG
Above	UPDATED	1/21/09	JLG
Above	UPDATED	6/1/09	JLG
Above	UPDATED	12/22/09	JLG
Above	UPDATED	1/27/11	JLG
Above	UPDATED	5/23/11	JLG
29	830	5/23/11	JLG

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See Search History Printout	7/31/08	JLG
Palm Inventor Search	7/31/08	JLG
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See Search History Printout	6/1/09	JLG
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See Search History Printout	1/27/11	JLG

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
Interference Search - See History Printout		5/23/11	JLG

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